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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Luan C. Tran			
				FILING DATE Filed herewith	GROUP Filed herewith		
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>HL</i>	AA	4,612,629	09/16/86	Harari			
<i>HL</i>	AB	4,785,342	11/15/88	Yamanaka et al.			
<i>HL</i>	AC	5,786,249	07/28/98	Dennison			
<i>HL</i>	AD	6,074,924	06/13/00	Dennison et al.			
<i>HL</i>	AE	5,272,367	12/21/93	Dennison et al.			
<i>HL</i>	AF	6,004,854	12/21/99	Dennison et al.			
<i>HL</i>	AG	5,683,927	11/04/97	Dennison et al.			
<i>HL</i>	AH	6,124,616	09/26/00	Dennison et al.			
<i>HL</i>	AI	5,747,855	05/05/98	Dennison et al.			
<i>HL</i>	AJ	5,534,449	07/09/96	Dennison et al.			
<i>HL</i>	AK	5,7706,806	07/07/98	Dennison et al.			
<i>HL</i>	AL	5,773,863	06/60/98	Burr et al.			
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
<i>HL</i>	AM	EP 0 717 448 A1	06/19/96	EPO			
<i>HL</i>	AN	WO 98/29897	07/09/98	PCT			
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
<i>HL</i>	AQ		Silicon Processing for the VLSI Era, Vol. III; "Punchthrough (Subsurface-DIBL) in Short-Channel MOSFETs"; undated; pp. 232-235, 238-244				
	AR						
	AS						
EXAMINER <i>hanna Schultze</i>				DATE CONSIDERED <i>10/17/02</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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